

1997 New York State Processing Sweet corn Research Association Progress Report
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TITLE: Screening of Commercial Processing Type Sweet Corn for Resistance to European Corn Borer and Other Pests

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ABSTRACT:

The results of this research show that commercial processing corn cultivars have differences in the level of resistance to European corn borer, with some varieties consistently displaying greater resistance as measured by total number of larvae, ear damage, and tunneling damage.

This was a collaborative effort to determine levels of resistance to European corn borer in commercial processing sweet corn cultivars that are commonly grown in New York and the Northeast. Selected cultivars were monitored for damage caused by artificial infestations of European corn borer. Damage was evaluated to determine the feasibility of using commercial cultivars in back crosses with other resistance bearing lines. Investigations into the mechanisms of resistance were initiated by correlating resistance expression with corn ear morphology.

For a printed copy of the entire report, please contact the NYS IPM office at:

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